Notice of Allowability	Application No.	D. Applicant(s)	
	10/538,559	0/538,559 NISHIZAWA, HIROSHI	
	Examiner	Art Unit	
	 Warren K. Fenwick	2862	
The MAILING DATE of this communication apperature All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIOT OF THE OFFICE OF UPON PETITION BY THE OFFICE OF THE OFFICE OF	(OR REMAINS) CLOSED in thi or other appropriate communic IGHTS. This application is subj	s application. If not included ation will be mailed in due course. TH	IIS liative
1. This communication is responsive to <u>amendment filed on (</u>	<u>09/10/2007</u> .		
2. The allowed claim(s) is/are <u>1-14</u> .			
 3. Acknowledgment is made of a claim for foreign priority unal All b) Some* c) None of the: 1. Certified copies of the priority documents have 2. Certified copies of the priority documents have 3. Copies of the certified copies of the priority documents have International Bureau (PCT Rule 17.2(a)). * Certified copies not received: 	been received. been received in Application N	o	ıe
Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.	of this communication to file a re IENT of this application.	eply complying with the requirements	
4. A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which give	itted. Note the attached EXAMII es reason(s) why the oath or de	NER'S AMENDMENT or NOTICE OF claration is deficient.	
5. CORRECTED DRAWINGS (as "replacement sheets") mus (a) including changes required by the Notice of Draftspers 1) hereto or 2) to Paper No./Mail Date (b) including changes required by the attached Examiner's Paper No./Mail Date	on's Patent Drawing Review (F	he Office action of	
Identifying indicia such as the application number (see 37 CFR 1. each sheet. Replacement sheet(s) should be labeled as such in t	.84(c)) should be written on the di he header according to 37 CFR 1.	rawings in the front (not the back) of 121(d).	
 DEPOSIT OF and/or INFORMATION about the deposit attached Examiner's comment regarding REQUIREMENT I 	sit of BIOLOGICAL MATERIA FOR THE DEPOSIT OF BIOLO	AL must be submitted. Note the GICAL MATERIAL.	
Attachment(s)	6. 17.		
 Notice of References Cited (PTO-892) Notice of Draftperson's Patent Drawing Review (PTO-948) 	5. Notice of Inform	• •	
	6.	Date	
 Information Disclosure Statements (PTO/SB/08), Paper No./Mail Date 	7. 🛛 Examiner's Ame	endment/Comment	
 Examiner's Comment Regarding Requirement for Deposit of Biological Material 	8. Examiner's Stat	ement of Reasons for Allowance	
	9.		

Application/Control Number:

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Detailed Action

Response to Amendment

1. Examiner has acknowledged and reviewed applicant's submission (filed on 09/10/2007) of the revisions to the specification. Examiner has thereby withdrawn the objections to applicant's specification, as cited in the first non-final office action.

Reasons for Allowance

2. Examiner has acknowledged and reviewed applicant's remarks on the first non-final office action. The following is an examiner's statement of reasons for allowance:

The primary reason for allowance of claims 1-14 is the claim language found in claims 1 and 3, for an imaging apparatus comprising: a semiconductor imaging device which converts incident light to an electrical signal; an optical filter which is opposed to an incident surface of a semiconductor imaging device and transmits light of a certain wavelength; and a fixing member fixing an optical filter by means of adhesion using a filler-containing adhesive. Most notably, an adhesive filler particle diameter is smaller than or equal to a pixel size of said semiconductor imaging device.

Also, the primary reason for allowance of claims 1-14 is the claim language found in claims 7 and 11 for a method of manufacturing an imaging apparatus comprising the steps of: providing a substrate; providing a semiconductor imaging device; mounting a semiconductor imaging device to the substrate; providing an optical filter; selecting a filler-containing adhesive based on a diameter of the filler being smaller than or equal to the pixel size; mounting the optical filter to a substrate by means of adhesion using the filler-containing adhesive.

3. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

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4. The application is in condition for allowance except for the following formal matters presented in the next two paragraphs.

Examiner's Amendment

- 5. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.
- Authorization for this examiner's amendment was given to edit typographic errors presented in claims 8-10 and 12, in a telephone interview with Mr. Aaron Fishman on 11/27/2007. Subsequent to the telephone call, claims 8-10 and 12 were amended, accordingly, and are presented below.

Examiner's Amendments to the Claims:

Claim 8 (Currently Amended): The method of claim 87, wherein the diameter of the filler is larger than or equal to 1/2 of the pixel size.

Claim 9 (Currently Amended): The method of claim 87, wherein the filler is spherical in shape.

Claim 10 (Currently Amended): The method of claim 87, wherein the diameter of the filler is smaller than or equal to 3.8 µm.

Claim 12 (Currently Amended): The method of claim 121, wherein the diameter of the filler is larger than or equal to 1/2 of the pixel size.

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Telephone Numbers

- 7. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Warren K. Fenwick whose telephone number is 571-270-3040. The examiner can normally be reached on Mon- Fri 8:30A to 6:00P, Eastern Time (GMT-5).
- 8. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Patrick J. Assouad can be reached on 571-272-2210. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.
- 9. Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

molenky

WKF

William Perkey Primary Examiner